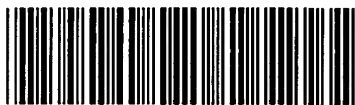


Search Notes

Application/Control No.

10/643,078

Examiner

David Q. Nguyen

Applicant(s)/Patent under
Reexamination

NAKAZAWA ET AL.

Art Unit

2617

SEARCHED

Class	Subclass	Date	Examiner
455	423-425	9/12/2006	DN
455	63.1	9/12/2006	DN
455	63.2	9/12/2006	DN
455	67.11	9/12/2006	DN
455	67.13	9/12/2006	DN
455	67.7	9/12/2006	DN
455	560	9/12/2006	DN
455	561	9/12/2006	DN
370	278	9/12/2006	DN

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner
PGPUB text search-See interference search printout		9/12/2006	DN

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
East-See Search History Printout	9/12/2006	DN
East-See Interference search Printout	9/12/2006	DN